### **ABSOLUTE MAXIMUM RATINGS**

Pin Voltages	
V <sub>DD</sub> to DGND, AGNDA, AGNDB	0.3V to +17V
V <sub>SS</sub> to DGND, AGNDA, AGNDB (Note 1)	+0.3V to -17V
VREFA, VREFB(V <sub>SS</sub> - 0.3)	$V$ ) to $(V_{DD} + 0.3V)$
AGNDA, AGNDB(DGND - 0.3)	$V$ ) to $(V_{DD} + 0.3V)$
VOUTA, VOUTB(V <sub>SS</sub> - 0.3)	$V$ ) to $(V_{DD} + 0.3V)$
RFBA, RFBB(V <sub>SS</sub> - 0.3)	$V$ ) to $(V_{DD} + 0.3V)$
SCLK, DIN, DOUT, LDAC, CS (DGND - 0.3)	$V$ ) to $(V_{DD} + 0.3V)$
DOUT Sink Current	20mA
Continuous Power Dissipation $(T_A = +70^{\circ}C)$	
Plastic DIP (derate 10.53mW/°C above +70	°C)842mW
Wide SO (derate 9.52mW/°C above +70°C)	762mW
CERDIP (derate 10.00mW/°C above +70°C)	)800mW

1	Operating Temperature Rang	es:	
	MAX532_C	0°C to	+70°C
	MAX532_E	40°C to	+85°C
	MAX532_MJE	55°C to	+125°C
	Junction Temperatures:		
	MAX532_C, E		+150°C
	MAX532_MJE		+175°C
	Storage Temperature Range.	65°C to	+160°C
	_ead Temperature (soldering,	, 10sec)	+300°C

Note 1: If Vss is open-circuited with VpD and either AGND applied, the Vss pin will float positive, exceeding the Absolute Maximum Ratings. A Schottky diode connected between Vss and GND ensures the maximum ratings will not be exceeded.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

### **ELECTRICAL CHARACTERISTICS**

( $V_{DD}$  = 11.4V to 16.5V,  $V_{SS}$  = -11.4V to -16.5V, AGNDA = AGNDB = DGND = 0V, VREFA and VREFB = +10V,  $R_L$  =  $2k\Omega$ ,  $C_L$  = 100pF, VOUT\_ connected to RFB\_,  $T_A$  =  $T_{MIN}$  to  $T_{MAX}$ , unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS	
STATIC PERFORMANCE (Note 1)								
Resolution				12			Bits	
Relative Accuracy	INI		MAX532A			±1/2	LSB	
Relative Accuracy	IINL		MAX532B			±1	LSD	
Differential Nonlinearity		Guaranteed monotonic				±1	LSB	
		540111111	T <sub>A</sub> = +25°C, MAX532_			±2		
Zero-Code Offset Error		DAC latch loaded with all 0s	$T_A = T_{MIN}$ to $T_{MAX}$ , MAX532A			±3	mV	
		WILLI All OS	$T_A = T_{MIN}$ to $T_{MAX}$ , MAX532B			±4		
Zero-Code Offset Temperature Coefficient		DAC latch loaded with all (	DAC latch loaded with all 0s				μV/°C	
		T <sub>A</sub> = +25°C, DAC latch loaded with all 1s	MAX532A			±2	LSB	
Gain Frror			MAX532B			±5		
Gaill Elloi		TA - TMIN TO TMAX, DAG	MAX532A			±4		
			MAX532B			±7		
Gain-Error Temperature Coefficient					±2		ppm/°C of FSR	
REFERENCE INPUTS (VREFA, VREFB)								
VREFA, VREFB Input Resistance				8	10	13	kΩ	
VREFA, VREFB Input Resistance Matching					±0.5	±3.0	%	

### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{DD}=11.4V~to~16.5V,~V_{SS}=-11.4V~to~-16.5V,~AGNDA=AGNDB=DGND=0V,~VREFA~and~VREFB=+10V,~R_L=2k\Omega,~C_L=100pF,~VOUT\_~connected~to~RFB\_,~T_A=T_{MIN}~to~T_{MAX},~unless~otherwise~noted.)$ 

PARAMETER	SYMBOL	COND	ITIONS	MIN	TYP	MAX	UNITS
DIGITAL INPUTS (SCLK,	DIN, LDAC,	CS)					
Input High Voltage	V <sub>INH</sub>			2.4			V
Input Low Voltage	V <sub>INL</sub>					0.8	V
Input Current		Digital inputs at 0V or V <sub>DD</sub>				±1	μΑ
Input Capacitance (Note 2)						8	pF
DIGITAL OUTPUT (DOUT	(Note 3)						
0 1 1 1 1 1 1 1 1 1 1 1 1		I <sub>SINK</sub> = 5mA			0.08	0.4	.,
Output Voltage Low	V <sub>OL</sub>	I <sub>SINK</sub> = 16mA			0.2		- V
Output High Leakage	I <sub>LKG</sub>	$V_{DOUT} = 0V \text{ to } V_{DD}$				±10	μΑ
Output High Capacitance (Note 2)	C <sub>OUT</sub>					15	pF
ANALOG OUTPUTS (VOL	ITA, VOUTI	3)					
DC Output Impedance					0.2		Ω
Short-Circuit Current		VOUTA, VOUTB connected	to AGNDA, AGNDB		20		mA
				(V <sub>DD</sub> - 2	.5)		
Output Voltage Swing	Output Voltage Swing				.5)		V
POWER REQUIREMENTS	<u> </u>						
Positive Supply Voltage	V <sub>DD</sub>			11.4		16.5	V
Negative Supply Voltage	V <sub>SS</sub>			-11.4		-16.5	V
$\Delta Full \ scale/\Delta V_{DD}, \ V_{DD} = 11.4V \ to \ 16.5V, \ VREF = -8 \ DAC \ latches \ loaded \ with \ all \ 1s$ Power-Supply Rejection PSR					±0.035	- LSB/%	
		DAC latches loaded with al		vREF = 8.9V, ±0.035			
Positive Supply Current	I <sub>DD</sub>	Output unloaded			5	10	mA
Negative Supply Current	I <sub>SS</sub>	Output unloaded			4	6	mA
AC CHARACTERISTICS							
Voltage-Output Settling Time		Settling time to within 1/2 L latch alternately loaded wit	SB of final DAC value; DAC h all 0s and all 1s		2.5		μs
Slew Rate					8		V/µs
Digital-to-Analog Glitch Impulse		DAC latch alternately loade		60		nV-s	
Channel-to-Channel		VREFA to VOUTB	VREFA = 20V <sub>p-p</sub> 10kHz sine wave; DAC latches loaded with all 0s		-100		- dB
Isolation		VREFB to VOUTA	VREFB = 20V <sub>p-p</sub> 10kHz sine wave; DAC latches loaded with all 0s		-100		- ub

### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{DD}=11.4V~to~16.5V,~V_{SS}=-11.4V~to~-16.5V,~AGNDA=AGNDB=DGND=0V,~VREFA~and~VREFB=+10V,~R_L=2k\Omega,~C_L=100pF,~VOUT\_~connected~to~RFB\_,~T_A=T_{MIN}~to~T_{MAX},~unless~otherwise~noted.)$ 

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Multiplying Feedthrough Error		VREF = 20V <sub>p-p</sub> 10kHz sine wave; DAC latch loaded with all 0s		-77		dB
Unity-Gain Small-Signal Bandwidth		VREF = 100mV <sub>p-p</sub> sine wave; DAC latch loaded with all 1s		1.0		MHz
Full-Power Bandwidth		VREF = 20V <sub>p-p</sub> sine wave; DAC latch loaded with all 1s		125		kHz
Total Harmonic Distortion	THD	VREF = 6V <sub>RMS</sub> , 1kHz sine wave; DAC latch loaded with all 1s		-90		dB
Digital Feedthrough		CS = 1; transitions on SCLK, LDAC, DIN		1.1		nV-s
Digital Crosstalk		DACA code all 1s, DACB code transition from all 0s to all 1s		10		nV-s
Output Noise Voltage		0.1Hz to 10Hz		2		$\mu V_{RMS}$

Note 1: Static performance tested at V<sub>DD</sub> = +15V, V<sub>SS</sub> = -15V. Performance over supplies guaranteed by PSR test. Note 2: Guaranteed by design. Not subject to production testing. Note 3: Open-drain output.

### **TIMING CHARACTERISTICS**

( $V_{DD}$  = 11.4V to 16.5V,  $V_{SS}$  = -11.4V to -16.5V, AGNDA = AGNDB = DGND = 0V) (Notes 4, 5)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
SCLK Clock Frequency	fclk				6.25	MHz
SCLK Pulse Width High	t <sub>CH</sub>		80			ns
SCLK Pulse Width Low	t <sub>CL</sub>		80			ns
DIN to SCLK Rise Setup Time	t <sub>DS</sub>		50			ns
DIN to SCLK Rise Hold Time	t <sub>DH</sub>		0			ns
CS Fall to SCLK Rise Setup Time	t <sub>CSS0</sub>		50			ns
CS Rise to SCLK Rise Setup Time	t <sub>CSS1</sub>		50			ns
SCLK Fall to CS Fall Hold Time	t <sub>CSH0</sub>		5			ns
SCLK Rise to CS Rise Hold Time	t <sub>CSH1</sub>		80			ns
CS Pulse Width High	t <sub>CSW</sub>		120			ns
SCLK Fall to DOUT Valid (Note 6)	t <sub>DO</sub>	$C_L = 20pF$ , $R_{PULL-UP} = 1k\Omega$ to 5V	0		200	ns
CS Fall to DOUT Enable (Note 7)	t <sub>DV</sub>	$C_L = 20pF$ , $R_{PULL-UP} = 1k\Omega$ to 5V			100	ns
CS Rise to DOUT Disable (Note 7)	t <sub>TR</sub>	$C_L = 20pF$ , $R_{PULL-UP} = 1k\Omega$ to 5V			60	ns
LDAC Pulse Width Low	t <sub>LDAC</sub>		60			ns
CS Rise to LDAC Fall Setup Time	t <sub>LDACS</sub>		100			ns

**Note 4:** All input signals are specified with  $t_R = t_F \le 5$ ns. Logic input swing is 0V to 5V.

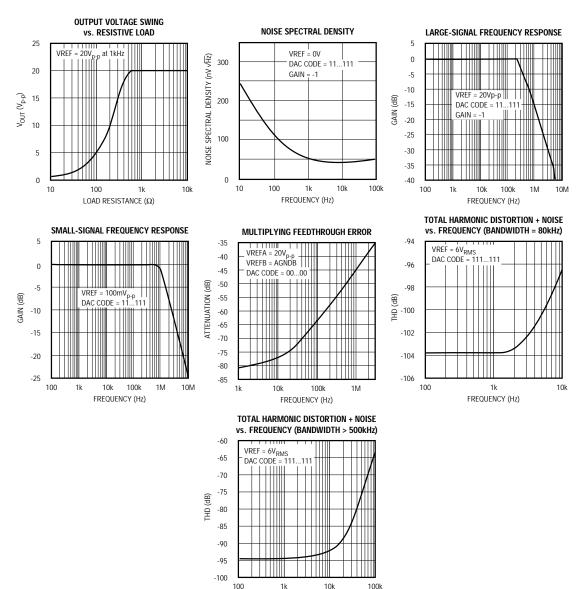
Note 5: See Figure 1.

Note 6: Timing is for SCLK fall to DOUT fall to 0.8V, or for SCLK fall to DOUT rise to 2.4V. Additional time must be added for any larger passive RC pull-up delay.

Note 7: DOUT enable: DOUT falls to 4.5V from 5.0V. DOUT disable: DOUT rises to 0.5V from 0V.

## Typical Operating Characteristics

(V<sub>DD</sub> = 15V, V<sub>SS</sub> = -15V, R<sub>L</sub> =  $2k\Omega$ , C<sub>L</sub> = 100pF, unless otherwise noted.)

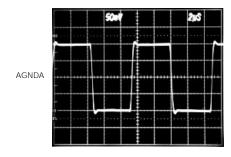


FREQUENCY (Hz)

### Typical Operating Characteristics (continued)

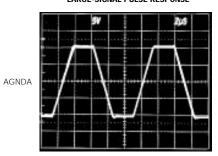
 $(V_{DD} = 15V, V_{SS} = -15V, R_L = 2k\Omega, C_L = 100pF, unless otherwise noted.)$ 

### SMALL-SIGNAL PULSE RESPONSE



 $A = V_{OUTA}, 50mV/div \\ TIMEBASE = 2\mu s/div \\ V_{REFA} = \pm 100mV \ SQUARE \ WAVE$ 

#### LARGE-SIGNAL PULSE RESPONSE



A = VOUTA, 5V/div TIMEBASE =  $2\mu$ s/div VREFA =  $\pm 10$ V SQUARE WAVE

### \_Pin Description

PIN	NAME	FUNCTION
1	RFBA	Feedback Resistor for DACA
2	VREFA	Reference Input for DACA
3	VOUTA	Voltage Output for DACA
4	AGNDA	Analog Ground for DACA
5	AGNDB	Analog Ground for DACB
6	VOUTB	Voltage Output for DACB
7	VREFB	Reference Input for DACB
8	RFBB	Feedback Resistor for DACB
9	V <sub>SS</sub>	Negative Supply Voltage
10	DGND	Digital Ground
11	SCLK	Serial Clock Input
12	DOUT	Serial Data Output. Open-drain N-channel MOSFET output: requires external pull-up resistor. Data on DOUT changes on the falling edge of SCLK. Serial output data is delayed 24 clock cycles from DIN.
13	DIN	Serial Data Input. CMOS- and TTL-compatible input. Data is clocked into DIN on the rising edge of SCLK. $\overline{\text{CS}}$ must be low for data to be clocked in.
14	CS	Chip-Select Input, active low. Data is shifted in and out when $\overline{CS}$ is low. DAC latches are updated when $\overline{CS}$ is high and $\overline{LDAC}$ is low.
15	LDAC	Asynchronous Load DAC Input, active low. DAC latches are updated when $\overline{\textbf{CS}}$ is high and $\overline{\textbf{LDAC}}$ is low.
16	V <sub>DD</sub>	Positive Supply Voltage

## \_Timing Diagrams

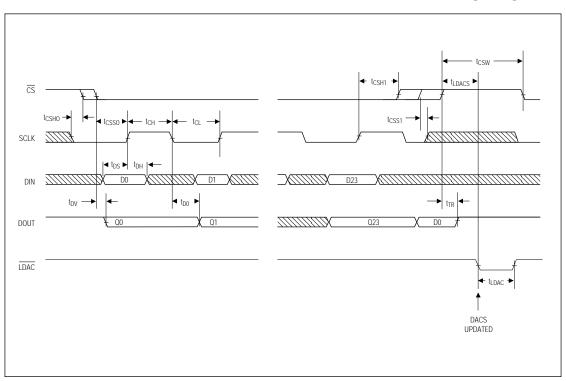


Figure 1. Timing Diagram

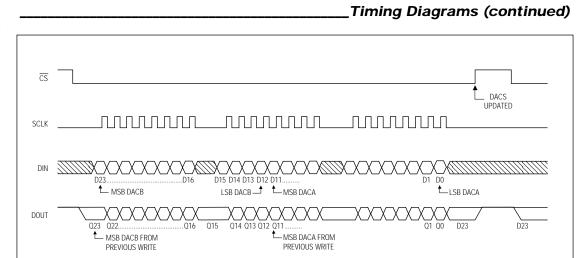


Figure 2. 3-Wire Interface Timing Diagram (LDAC = DGND)

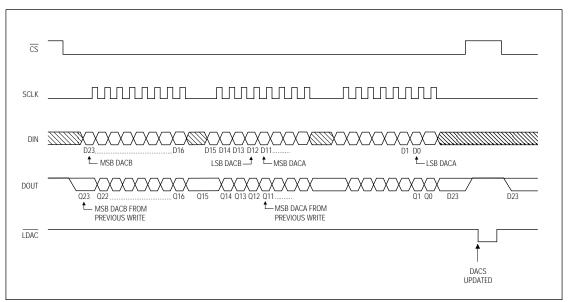


Figure 3. 4-Wire Inferface Timing Diagam

· \_\_\_\_\_MXIM

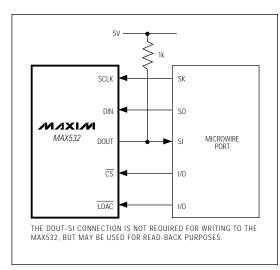


Figure 4. Connections for Microwire

### \_Detailed Description Digital Interface

The MAX532 is Microwire and SPI compatible (Figures 4 and 5). Both DACs are programmed by writing three 8-bit words (see Figures 2 and 3, and the *Functional Diagram*). Serial data is clocked into the data registers MSB first, with DACB information preceding DACA information. Data is clocked in on the rising edge of SCLK while  $\overline{\textbf{CS}}$  is low. With  $\overline{\textbf{CS}}$  high, data can not be clocked into DIN, and DOUT is high impedance. SCLK can be driven at rates up to 6.25MHz.

The MAX532 uses either a 3-wire or a 4-wire serial interface. Three wires may be used (\$\overline{CS}\$, DIN, SCLK) by tying \$\overline{LDAC}\$ low. With \$\overline{LDAC}\$ low, the DACs are updated simultaneously when \$\overline{CS}\$ goes high (see Figure 2 and the \*Functional Diagram\*). The 3-wire interface may be used if the MAX532 is used alone, or if two or more MAX532s are cascaded (DOUT of one device tied to DIN of the other) (Figure 6).

The 4-wire interface (LDAC, CS, DIN, SCLK) is required if several serial devices are tied to the same data line, and it is desirable to update them simultaneously (Figure 7). With the 4-wire interface, the DACs are updated when LDAC goes low (see Figure 3 and the Functional Diagram).

A serial output, DOUT, allows cascading of two or more MAX532s and allows read-back of the data written to

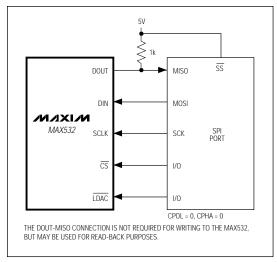


Figure 5. Connections for SPI

the device's 24-bit shift register. The data at DOUT is delayed 24 clock cycles from the data at DIN (see Figures 2 and 3, and the *Functional Diagram*). DOUT is an open-drain N-channel MOSFET that requires an external pull-up resistor (typically  $1k\Omega$  if pulled up to +5V, and  $3k\Omega$  if pulled up to +12V or +15V). Logic levels are guaranteed with sink currents up to 5mA (see *Electrical Characteristics*). Output data changes on the falling edge of SCLK when  $\overline{CS}$  is low. If  $\overline{CS}$  is high, DOUT is three-state (high-impedance).

### **Daisy-Chaining Devices**

Any number of MAX532s can be daisy-chained by connecting the DOUT pin of one device (with a pull-up resistor) to the DIN pin of the following device in the chain (Figure 6).

When daisy-chaining devices,  $t_{CSS0}$  ( $\overline{\textbf{CS}}$  low to SCLK high), must be the greater of  $t_{DV}$  +  $t_{DS}$  or  $t_{DS}$  + ( $t_{RC}$  +  $t_{TR}$  -  $t_{CS}$ ), where  $t_{CSW}$  is the  $\overline{\textbf{CS}}$  pulse width used in the system and the term ( $t_{RC}$  +  $t_{TR}$  -  $t_{CSW}$ ) accounts for the time spent charging the DOUT capacitance with the external pull-up resistor. So, for  $t_{RC}$  < 250ns,  $t_{CSS0}$  is simply  $t_{DV}$  +  $t_{DS}$ . Calculate  $t_{RC}$  using the following equation:

 $t_{RC} = R_P \times C \times ln (V_{PULL-UP}/(V_{PULL-UP} - 2.4V))$ 

where  $V_{PULL-UP}$  is the voltage that the pull-up resistor is connected to,  $R_P$  is the value of the pull-up resistor, and C is the capacitance at DOUT. Values of  $t_{RC}$  are given in Table 1.

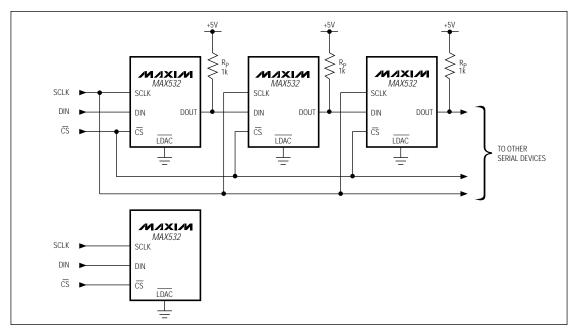


Figure 6. Daisy-chained or individual MAX532s are simultaneously updated by bringing  $\overline{CS}$  high when using the 3-wire interface  $(\overline{LDAC} = DGND)$ .

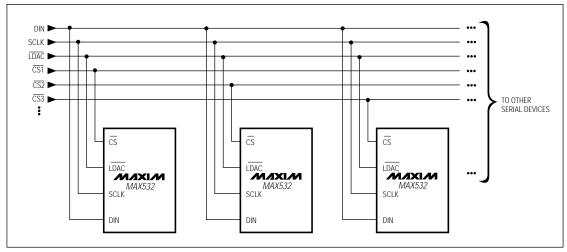


Figure 7. Multiple devices sharing a common DIN line may be simultaneously updated by bringing LDAC low. CS1, CS2, CS3, . . . , are driven separately, thus controlling which data are written to devices 1, 2, 3, . . . .

Table 1. t<sub>RC</sub> Delay Times

V <sub>PULL-UP</sub> (V)	C (pF)	<b>R</b> <sub>P</sub> ( <b>k</b> Ω)	t <sub>RC</sub> (ns)
4.5	20	1	15
4.5	35	1	27
4.5	50	1	38
4.5	100	1	76
4.5	150	1	114
11.4	20	3	14
11.4	35	3	25
11.4	50	3	35
11.4	100	3	71
11.4	150	3	106
13.5	20	3	12
13.5	35	3	21
13.5	50	3	29
13.5	100	3	59
13.5	150	3	88

With the values of  $t_{RC}$  given in Table 1,  $t_{CSS0}$  is always given by  $t_{DV}$  +  $t_{DS}.$  For different values of R or C,  $t_{RC}$  must be calculated to determine  $t_{CSS0}.$ 

Additionally, the maximum clock frequency is limited to

$$f_{CLK}$$
 (max) =  $\frac{1}{2 x (t_{DO} + t_{RC} - 15ns + t_{DS})}$ 

For example, with  $t_{RC}$  = 15ns (5V  $\pm 10\%$  supply with 1k $\Omega$  pull-up), the maximum clock frequency is 2MHz.

### Digital-to-Analog Section

Figure 8 shows a simplified circuit diagram for one of the DACs and the output amplifier.

A segmented scheme is used to improve linearity, whereby the two MSBs of the 12-bit data word are decoded to drive the three switches, SA, SB, and SC. The remaining ten bits drive the switches S0 through S9 in a standard R-2R ladder configuration.

Each of the switches, SA, SB, and SC, steers 1/4 of the total reference current with the remaining 1/4 passing through the R-2R section.

The output amplifier and feedback resistor perform the current-to-voltage conversion, giving the following:

$$VOUT_ = -D \times VREF_,$$

where \_ denotes A or B, and D is the fractional representation of the digital word. (D can be set from 0 to 4095/4096.)

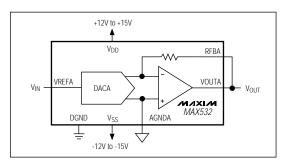


Figure 9. Unipolar Binary Operation

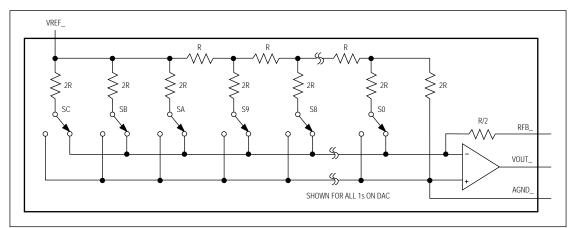


Figure 8. Simplified D/A Circuit Diagram

#### **Output Amplifiers**

The output amplifiers are stable with any combination of resistive loads  $\geq 2k\Omega$  and capacitive loads  $\leq 100 pF.$  They are internally compensated, and settle to  $\pm 0.01\%$  FSR (1/2LSB) in 2.5µs.

#### **Unipolar Configuration**

Figure 9 shows DACA connected for unipolar binary operation. Similar connections apply for DACB. When  $V_{\mbox{\scriptsize IN}}$  is an AC signal, the circuit performs two-quadrant multiplication. Table 2 shows the codes for this circuit.

#### **Bipolar Operation**

Figure 10 shows the MAX532 connected for bipolar operation. The coding is offset binary, as shown in Table 3. When  $V_{\mbox{\scriptsize IN}}$  is an AC signal, the circuit performs four-quadrant multiplication. To maintain gain error specifications, resistors R1, R2, and R3 should be ratiomatched to 0.01%.

Table 2. Unipolar Code Table

DAC Latch Contents	Analog Output, V <sub>OUT</sub>
MSB LSB	Analog Cutput, VO01
1111 1111 1111	-V <sub>IN</sub> x (4095/4096)
1000 0000 0000	-V <sub>IN</sub> x (2048/4096) = -1/2V <sub>IN</sub>
0000 0000 0001	-V <sub>IN</sub> x (1/4096)
0000 0000 0000	OV

 $1LSB = V_{IN}/4096$ 

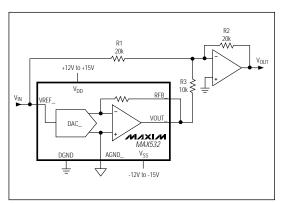


Figure 10. Bipolar Operation

### \_Applications Information

### Layout, Grounding, and Bypassing

For best system performance, use printed circuit boards with separate analog and digital ground planes. Wirewrap boards are not recommended. The two ground planes should be tied together at the low-impedance power-supply source, as shown in Figure 11.

The board layout should ensure that digital and analog signal lines are kept separate from each other as much as possible. Do not run analog and digital lines parallel to one another.

The output amplifiers are sensitive to high-frequency noise in the  $V_{DD}$  and  $V_{SS}$  power supplies. Bypass these supplies to the analog ground plane with  $0.1\mu F$  and  $10\mu F$  bypass capacitors. Minimize capacitor lead lengths for best noise rejection.

Table 3. Bipolar Code Table

DAC Latch Contents	Analog Output, V <sub>OUT</sub>			
MSB LSB	Analog Output, VOUT			
1111 1111 1111	+V <sub>IN</sub> x (2047/2048)			
1000 0000 0001	+V <sub>IN</sub> x (1/2048)			
1000 0000 0000	OV			
0111 1111 1111	-V <sub>IN</sub> x (1/2048)			
0000 0000 0000	-V <sub>IN</sub> + (2048/2048) = -V <sub>IN</sub>			

 $1LSB = V_{IN}/2048$ 

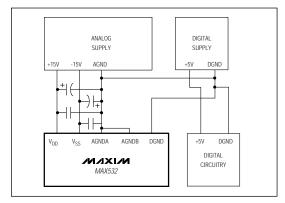


Figure 11. Power-Supply Grounding

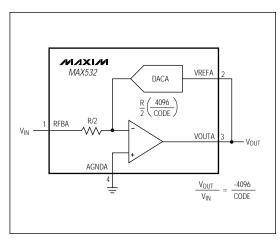


Figure 12. Programmable-Gain Amplifer

### Programmable-Gain Amplifier (PGA)

The DAC/amplifier combination, along with access to the feedback resistors, makes the MAX532 ideal as a programmable-gain amplifier. In this application, the DAC functions as a programmable resistor in the feedback loop. This type of configuration is shown in Figure 12, and is suitable for AC gain control. The DAC code controls the gain for the PGA. As the code decreases, the effective DAC resistance increases, and so the gain also increases. The transfer function is given by:

$$V_{OUT}/V_{IN} = -REQA/RFBA,$$

where RFBA is the value of the feedback resistor (R/2), and REQA is the effective DAC resistance controlled by the digital input code:

$$REQA = \frac{R}{2} \left( \frac{4096}{CODE} \right),$$

where CODE is the DAC code in decimal.

The transfer function is thus:

$$\frac{V_{OUT}}{V_{IN}} = \frac{-4096}{CODE}$$

The code may be programmed between 1 and (2<sup>12</sup> -1). The zero code is not allowed, as it results in an open-loop amplifier response.

#### Power-On Reset

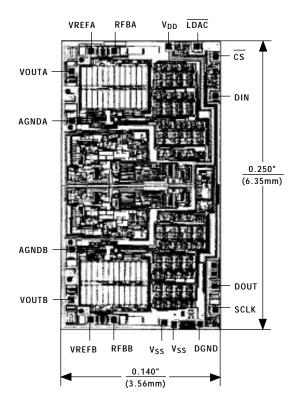
On power-up, the internal DAC latches are set to  $00\ldots.00.$ 

### \_Ordering Information (continued)

PART	TEMP. RANGE	PIN-PACKAGE	ERROR (LSBs)
MAX532AEPE	-40°C to +85°C	16 Plastic DIP	±1/2
MAX532BEPE	-40°C to +85°C	16 Plastic DIP	±1
MAX532AEWE	-40°C to +85°C	16 Wide SO	±1/2
MAX532BEWE	-40°C to +85°C	16 Wide SO	±1
MAX532AMJE	-55°C to +125°C	16 CERDIP**	±1/2
MAX532BMJE	-55°C to +125°C	16 CERDIP**	±1

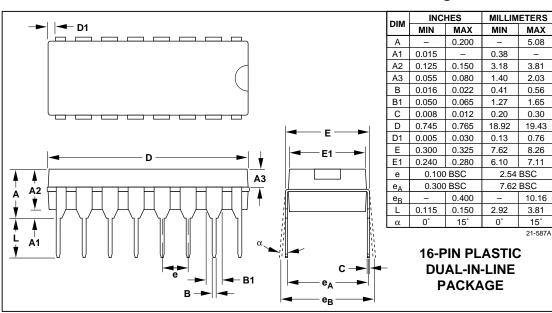
<sup>\*\*</sup>Contact factory for availability and processing to MIL-STD-883B.

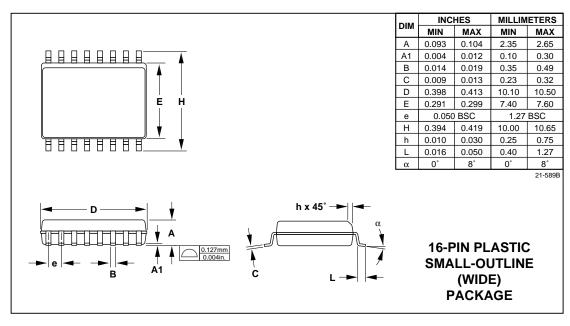
## \_\_Chip Topography



TRANSISTOR COUNT: 1324; SUBSTRATE CONNECTED TO V<sub>DD</sub>.

### \_Package Information





Maxim cannot assume responsibility for use of any circuitry other than circuitry entirely embodied in a Maxim product. No circuit patent licenses are implied. Maxim reserves the right to change the circuitry and specifications without notice at any time.

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